TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2SC2290

2~30MHz SSB LINEAR POWER AMPLIFIER APPLICATIONS (LOW SUPPLY VOLTAGE USE)

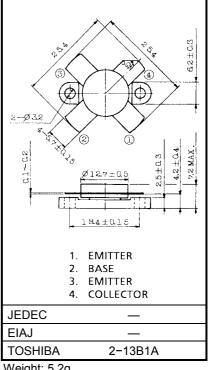
Specified 12.5V, 28MHz Characteristics

Output Power $: Po = 60W_{PEP} (Min.)$ Power Gain : Gp = 11.8dB (Min.) $\eta_{\rm C} = 35\%$ (Min.) Collector Efficiency Intermodulation Distortion: IMD = -30dB (Max.)

MAXIMUM RATINGS (Tc = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	V_{CBO}	45	V
Collector-Emitter Voltage	V _{CES}	45	V
Collector-Emitter Voltage	V _{CEO}	18	V
Emitter-Base Voltage	V _{EBO}	4	V
Collector Current	Ic	20	Α
Collector Power Dissipation	P _C	175	W
Junction Temperature	Tj	175	°C
Storage Temperature Range	T _{stg}	-65~175	°C

Unit in mm



Weight: 5.2g

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damage to property.

In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..

The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal actions of the continuous products are used within specified operating ranges as set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA products reconstructions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA products reconstructions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA products reconstructions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA products reconstructions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..

The information contained herein is subject to change without notice.

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ELECTRICAL CHARACTERISTICS (Tc = 25°C)

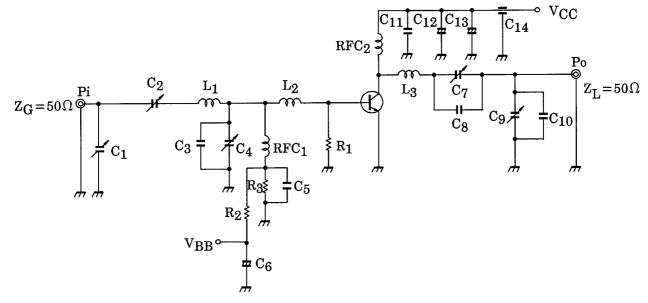
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector-Emitter Breakdown Voltage	V _(BR) CEO	I _C = 100mA, I _B = 0	18	_	_	V
Collector-Emitter Breakdown Voltage	V (BR) CES	I _C = 100mA, V _{EB} = 0	45	_	_	V
Emitter-Base Breakdown Voltage	V (BR) EBO	I _E = 1mA, I _C = 0	4	_	_	V
DC Current Gain	h _{FE}	V _{CE} = 5V, I _C = 10A *	10	_	150	_
Collector Output Capacitance	C _{ob}	V _{CB} = 12.5V, I _E = 0 f = 1MHz	_	_	500	pF
Power Gain	Gp	V_{CC} = 12.5V, f_1 = 28.000MHz, f_2 = 28.001MHz	11.8	13.8	-	dB
Input Power	Pi		_	2.5	4	W _{PEP}
Collector Efficiency	η _C	I _{idle} = 50mA Po = 60W _{PEP} (Fig.)	35	_	-	%
Intermodulation Distortion	IMD		_	_	-30	dB
Series Equivalent Input Impedance	Z _{in}	V _{CC} = 12.5V, f ₁ = 28.000MHz, f ₂ = 28.001MHz	_	1.02 -j0.17	_	Ω
Series Equivalent Output Impedance	Z _{out}	Po = 60W _{PEP}	_	0.86 -j0.21		Ω

^{*} Pulse Test: Pulse Width ≤ 100µs, Duty Cycle ≤ 3%

CAUTION

Beryllia Ceramics is used in this product. The dust or vapor can be dangerous to humans. Do not break, cut, crush or dissolve chemically. Dispose of this product properly according to law. Do not intermingle with normal industrial or domestic waste.

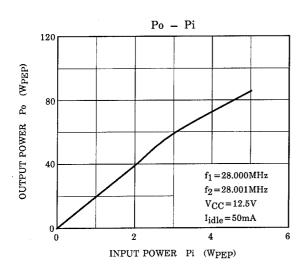
Fig. Pi TEST CIRCUIT

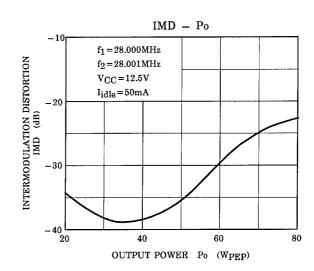


: ϕ 0.8 ENAMEL COATED COPPER WIRE, 9ID, 6T $C_1, C_2, C_4, C_7 : 7 \sim 150 pF$ L_1 : ϕ 1 SILVER PLATED COPPER WIRE, 9ID, 2T : 250pF L_2 C_3 : ϕ 1.5 ENAMEL COATED COPPER WIRE, 9ID, 5T : $0.4\mu F$ L_3 C_5 RFC₁ : ϕ 0.8 ENAMEL COATED COPPER WIRE, 9ID, 20T : 100 µF 10WV C_6 RFC2 : $\phi 1.5$ ENAMEL COATED COPPER WIRE, 12ID, 15T C_8 : 150pF

 $\begin{array}{ccc} C_{12}, C_{13} & : & 22 \mu F \, 35 WV \\ C_{14} & : & 1000 pF \end{array}$

(FEED THROUGH)





CAUTION

These are only typical curves and devices are not necessarily guaranteed at these curves.